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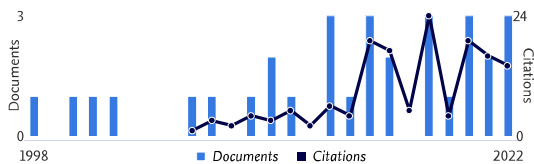
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Olikh, O., Lytvyn, P.

*Semiconductor Science and Technology*, 2022, 37(7), 075006

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**Intensification of iron–boron complex association in silicon solar cells under acoustic wave action**

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*Journal of Materials Science: Materials in Electronics*, 2022, 33(16), pp. 13133–13142

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**Estimation for iron contamination in Si solar cell by ideality factor: Deep neural network approach**

Olikh, O., Lozitsky, O., Zavhorodnii, O.

*Progress in Photovoltaics: Research and Applications*, 2022, 30(6), pp. 648–660

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*Journal of Applied Physics*, 2021, 130(23), 235703

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*International Conference on Electrical, Computer, Communications and Mechatronics Engineering, ICECCME 2021*, 2021

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*Solid-State Electronics*, 2020, 165, 107712

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*Superlattices and Microstructures*, 2019, 136, 106309

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### Effect of ultrasound on reverse leakage current of silicon Schottky barrier structure





















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Ya Olikh, O., Voitenko, K.V., Burbelo, R.M., Olikh, Ja.M.

*Journal of Semiconductors*, 2016, 37(12), 122002

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